



Integrated Device Technology, Inc.
2975 Stender Way, Santa Clara, CA - 95054

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: SR0102-03 DATE: 2/26/01
Product Affected: SRAM 1M Product Family
Refer to attached list.
Manufacturing Location Affected: Salinas, California

Date Effective: 5/28/01

MEANS OF DISTINGUISHING CHANGED DEVICES:

- ☒ Product Mark
☐ Back Mark Die revision or top mark date code
☒ Date Code per attached change matrix.
☐ Other

Contact: George Snell
Title: Quality Assurance Manager
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Attachment: ☒ Yes ☐ No

Samples:

DESCRIPTION AND PURPOSE OF CHANGE:

- ☐ Die Technology
☐ Wafer Fabrication Process
☐ Assembly Process
☐ Equipment
☐ Material
☐ Testing
☒ Manufacturing Site
☐ Data Sheet
☐ Other

Transfer existing qualified product from Hillsboro, Oregon (Fab 4)
to Salinas, California (Fab 2) to enhance Fab capacity loading.
Refer to attached change matrix for each product transfer details.

RELIABILITY/QUALIFICATION SUMMARY:

Qualification of each product will verify that there is no impact to quality or reliability of the product.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____

☐ *Approval for shipments prior to effective date.*

Name/Date: _____

E-Mail Address: _____

Title: _____

Phone# /Fax# : _____

CUSTOMER COMMENTS:

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____

DATE: _____



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ATTACHMENT - PCN #: SR0102-03

PCN Summary

PCN Type: Fab Site Change

Commodity Memory

Forecast or Execute Execute

Planned or Unplanned Unplanned

Data Sheet Change None Expected

Detail of Change

Transfer existing or duplicate reticle sets of qualified products to the Salinas, California Wafer Fab Facility from Hillsboro, Oregon Wafer Fab Facility.

Part Name	Technology	Current Wafer Fab			Transfer Wafer Fab			Top Mark Distinction for change in Wafer Fab
		Manufacturing Site	Wafer Size	Die Revision	Manufacturing Site	Wafer Size	Die Revision	
71024S	Cmos 9	Hillsboro, OR	8 inch	M	Salinas, CA	6 inch	L	Die Rev "L" in Datecode
71028S	Cmos 9	Hillsboro, OR	8 inch	M	Salinas, CA	6 inch	L	Die Rev "L" in Datecode
71016S	Cmos 9	Hillsboro, OR	8 inch	N	Salinas, CA	6 inch	N	Datecode> N 0117x
71124S	Cmos 9	Hillsboro, OR	8 inch	N	Salinas, CA	6 inch	N	Datecode> N 0117x
71128S	Cmos 9	Hillsboro, OR	8 inch	N	Salinas, CA	6 inch	N	Datecode> N 0117x

Conversion schedule (Estimated)

	Sample Availability	Production Shipments
71024S	May 14, 2001	May 28, 2001
71028S	May 14, 2001	May 28, 2001
71016S	May 14, 2001	May 28, 2001
71124S	May 14, 2001	May 28, 2001
71128S	May 14, 2001	May 28, 2001



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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT - PCN #: SR0102-03

Qualification Plan : QS-0102-07

Expected Completion Date

Test Vehicle : 71024L

4/12/2001 5/12/2001

	Required Sample / # Fails	LOT #1	LOT #2
Option : 71028L			
Operating Life Test: Dynamic @+135°C, Vcc=6V for 750 hours	116 / 0		
Operating Life Test: Static @+135°C, Vcc=6V for 750 hours	116 / 0		
High Temp. Storage Life Test (Unbiased, 1000 hours @+150°C)	77 / 0		
Temperature Cycling: (-65°C to +150°C, 500 cycles)	45 / 0		
ESD Human Body Model	6 / 0		
ESD Charged Device Model	6 / 0		
Latch up: (Tested to 2X Vcc)	10 / 0		

Tests are completed for unshaded areas. Product released is based on qualification of initial lot.

Characterization Data: Characterization will be completed as part of product Qualification and data available upon request. Characterization will verify that there is no change to existing datasheet parameters.



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PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT - PCN #: SR0102-03

Qualification Plan : QS-0102-08

Expected Completion Date

Test Vehicle : 71016N

5/25/2001 6/25/2001

	Required Sample / # Fails	LOT #1	LOT #2
Option : 71124N, 71128N			
Operating Life Test: Dynamic @+135°C, Vcc=6V for 750 hours	116 / 0		
Operating Life Test: Static @+135°C, Vcc=6V for 750 hours	116 / 0		
High Temp. Storage Life Test (Unbiased, 1000 hours @+150°C)	77 / 0		
Temperature Cycling: (-65°C to +150°C, 500 cycles)	45 / 0		
ESD Human Body Model	6 / 0		
ESD Charged Device Model	6 / 0		
Latch up: (Tested to 2X Vcc)	10 / 0		

Tests are completed for unshaded areas. Product released is based on qualification of initial lot.

Characterization Data: Characterization will be completed as part of product Qualification and data available upon request. Characterization will verify that there is no change to existing datasheet parameters.